

REGULATORY COMPLIANCE



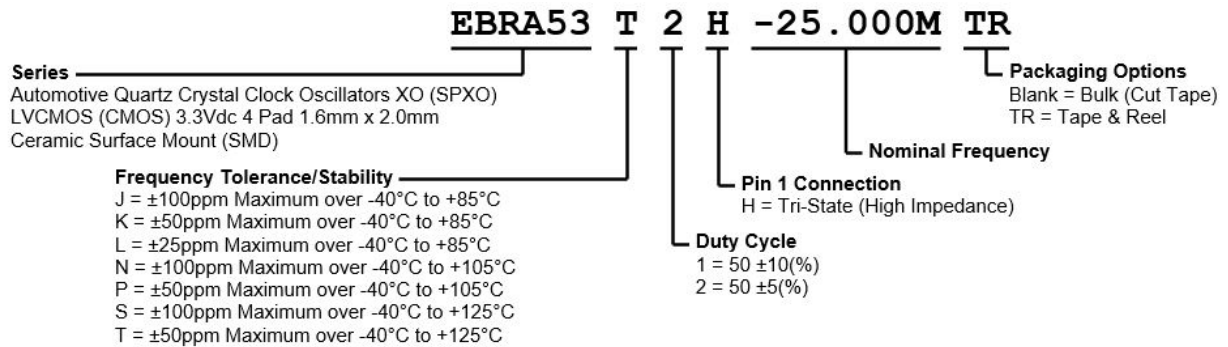
ITEM DESCRIPTION

Automotive Grade Quartz Crystal Clock Oscillators XO (SPXO) LVCMOS (CMOS) 3.3Vdc 4 Pad 1.6mm x 2.0mm Ceramic Surface Mount (SMD)

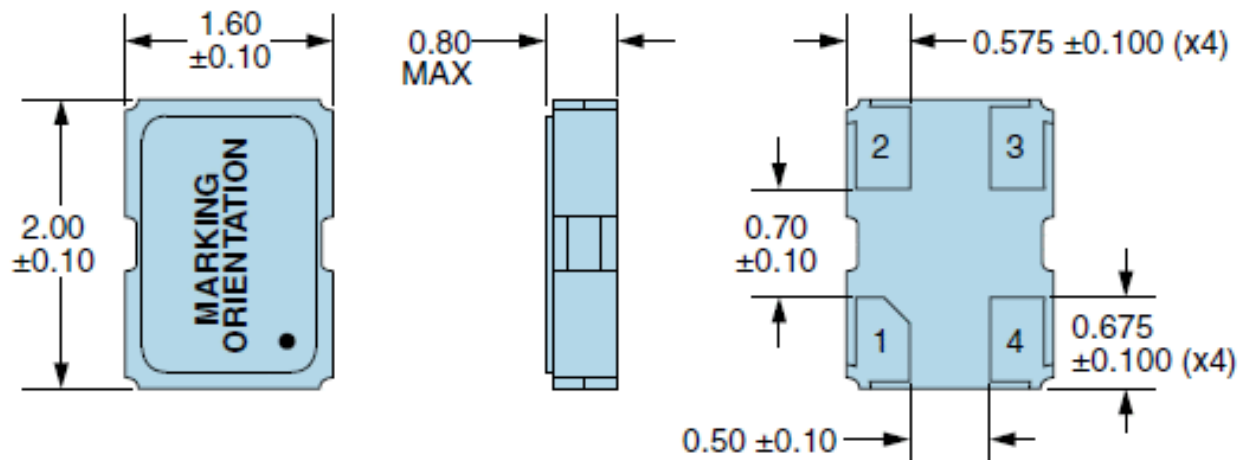
ELECTRICAL SPECIFICATIONS

| | |
|---|--|
| Nominal Frequency | 2.5MHz to 60MHz |
| Frequency Tolerance/Stability | Inclusive of all conditions: Calibration Tolerance (at 25°C), Frequency Stability over the Operating Temperature Range, Supply Voltage Change, Output Load Change, and First Year Aging at 25°C $\pm 100\text{ppm}$ Maximum over -40°C to $+85^{\circ}\text{C}$ $\pm 50\text{ppm}$ Maximum over -40°C to $+85^{\circ}\text{C}$ $\pm 25\text{ppm}$ Maximum over -40°C to $+85^{\circ}\text{C}$ $\pm 100\text{ppm}$ Maximum over -40°C to $+105^{\circ}\text{C}$ $\pm 50\text{ppm}$ Maximum over -40°C to $+105^{\circ}\text{C}$ $\pm 100\text{ppm}$ Maximum over -40°C to $+125^{\circ}\text{C}$ $\pm 50\text{ppm}$ Maximum over -40°C to $+125^{\circ}\text{C}$ |
| Aging at 25°C | $\pm 3\text{ppm/year}$ Maximum |
| Supply Voltage | 3.3Vdc $\pm 10\%$ |
| Input Current | Unloaded 10mA Maximum |
| Output Voltage Logic High (Voh) | IOH = -4mA 90% of Vdd Minimum |
| Output Voltage Logic Low (Vol) | IOL = +4mA 10% of Vdd Maximum |
| Rise/Fall Time | Measured at 20% to 80% of Waveform 6nSec Maximum |
| Duty Cycle | Measured at 50% of Waveform 50 $\pm 10\%$ 50 $\pm 5\%$ |
| Load Drive Capability | 15pF Maximum |
| Output Logic Type | CMOS |
| Pin 1 Connection | Tri-State (High Impedance) |
| Output Control Input Voltage Logic High (Vih) | 70% of Vdd Minimum or No Connect to Enable Output |
| Output Control Input Voltage Logic Low (Vil) | 30% of Vdd Maximum to Disable Output (High Impedance) |
| Standby Current | Without Load 10 μA Maximum |
| Period Jitter (RMS) | 5pSec Maximum |
| Period Jitter (pk-pk) | 30pSec Maximum |
| Start Up Time | 10mSec Maximum |
| Storage Temperature Range | -55°C to $+125^{\circ}\text{C}$ |

PART NUMBERING GUIDE



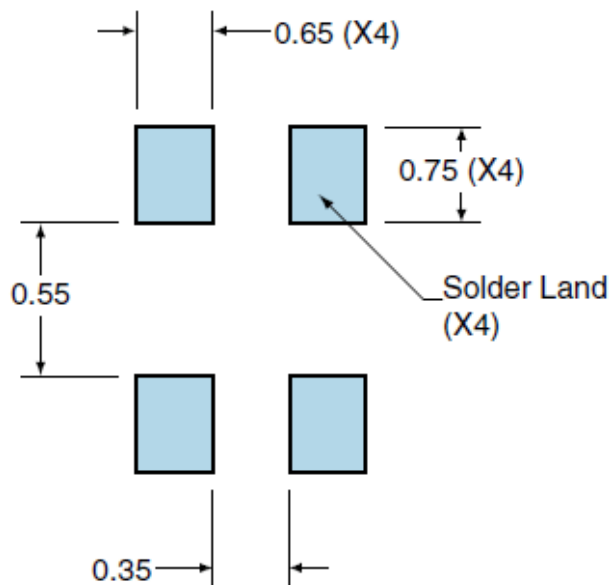
MECHANICAL DIMENSIONS



Seam Sealed

Terminal Plating Thickness: Gold (0.3 to 1.0µm) over Nickel (1.27 to 8.89µm).

SUGGESTED SOLDER PAD LAYOUT

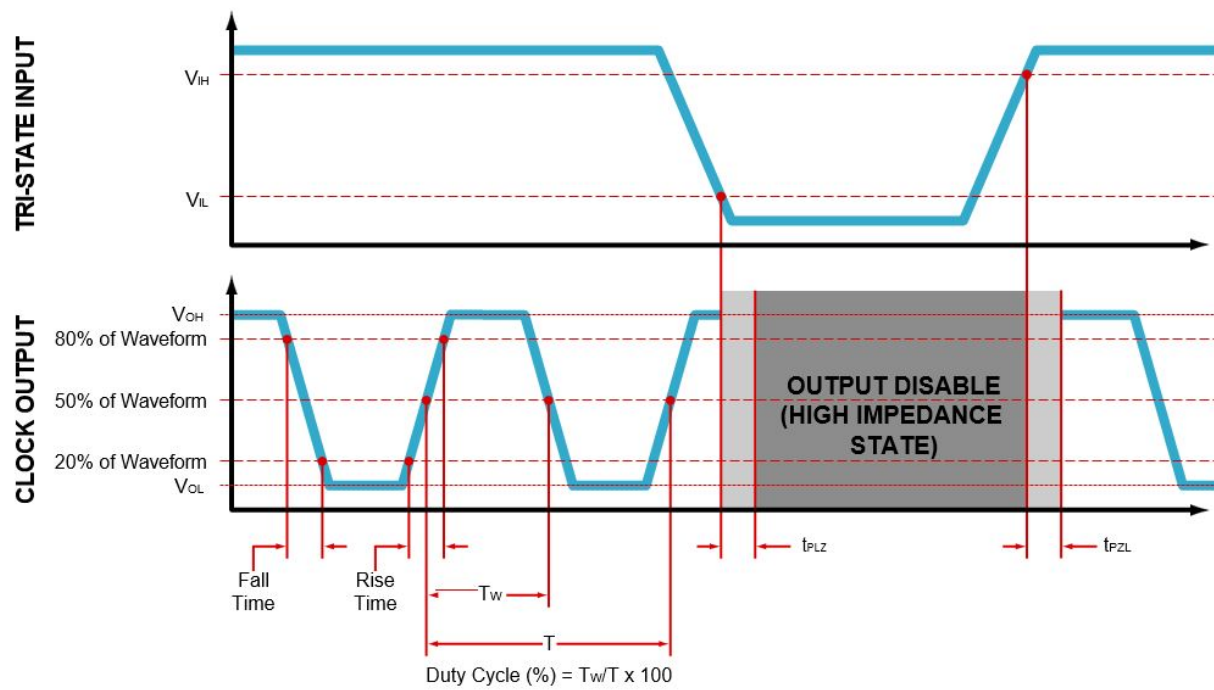


| PIN | CONNECTION |
|-----|----------------|
| 1 | Tri-State |
| 2 | Case/Ground |
| 3 | Output |
| 4 | Supply Voltage |

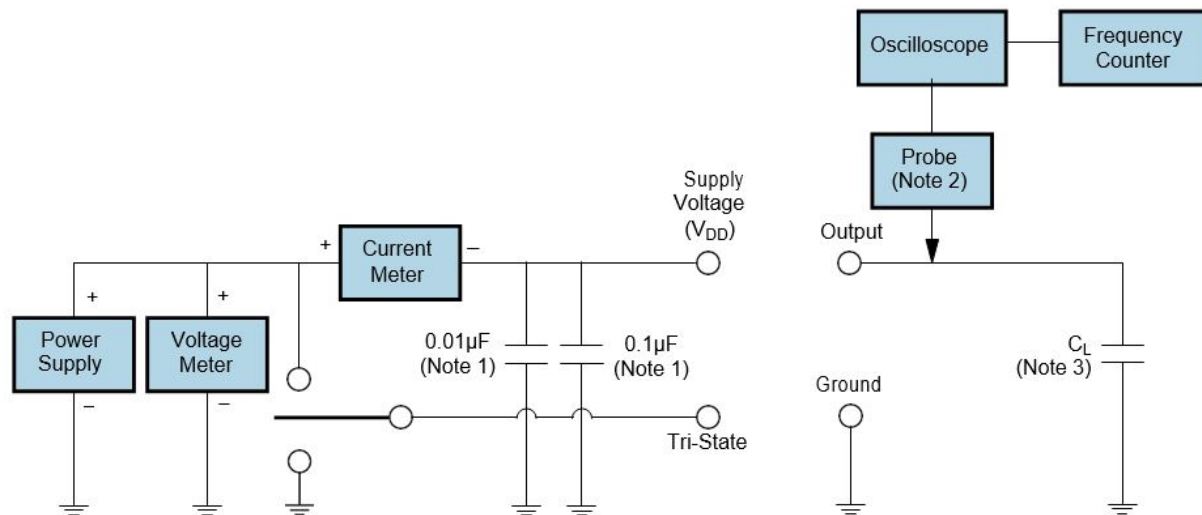
All Tolerances are ± 0.1

All Dimensions in Millimeters

OUTPUT WAVEFORM & TIMING DIAGRAM



TEST CIRCUIT FOR CMOS OUTPUT



Note 1: An external 0.01µF ceramic bypass capacitor in parallel with a 0.1µF high frequency ceramic bypass capacitor close (less than 2mm) to the package ground and supply voltage pin is required.

Note 2: A low capacitance (<12pF), 10X Attenuation Factor, High Impedance (>10Mohms), and High bandwidth (>300MHz) Passive probe is recommended.

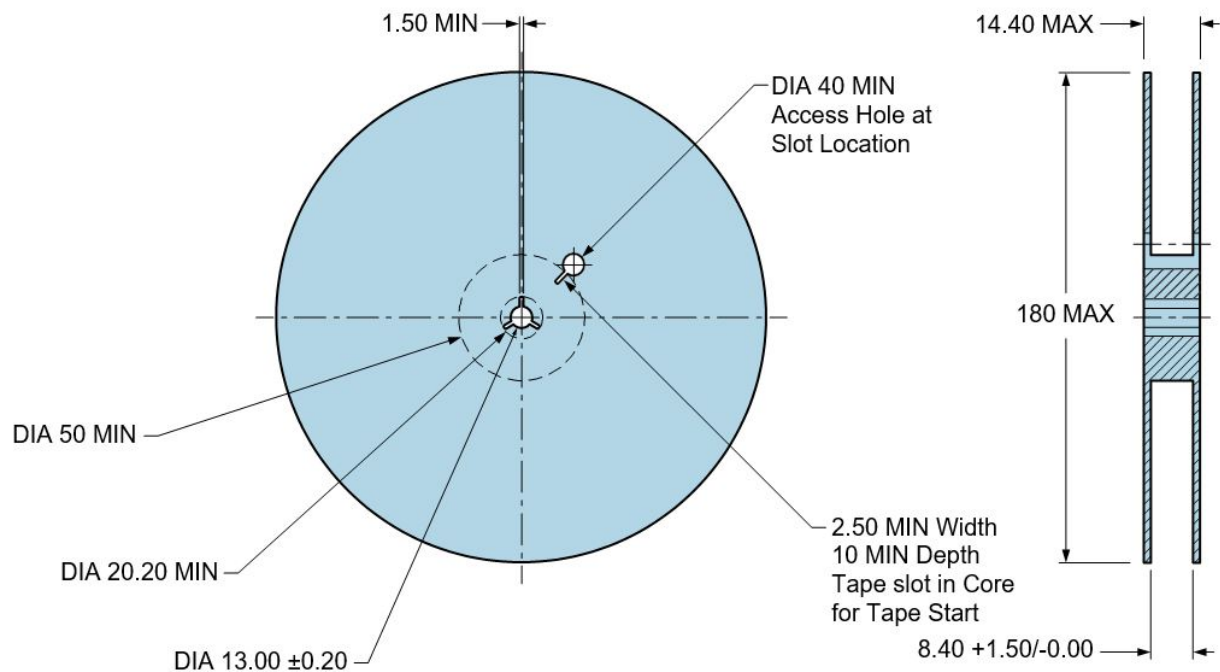
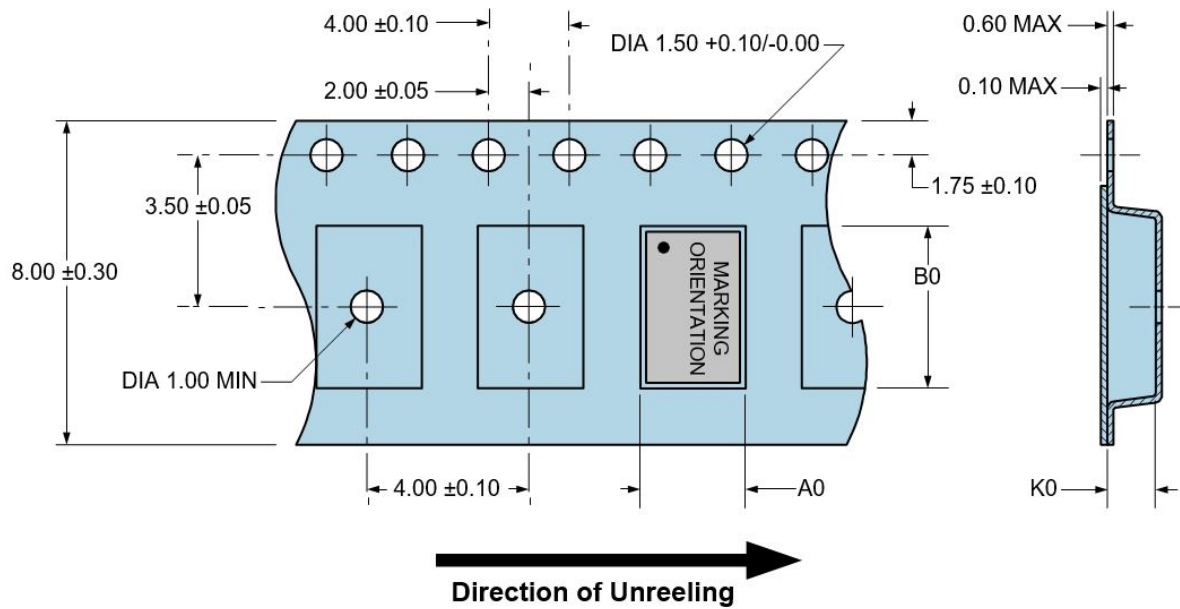
Note 3: Capacitance value C_L includes sum of all probe and fixture capacitance.

TAPE & REEL DIMENSIONS

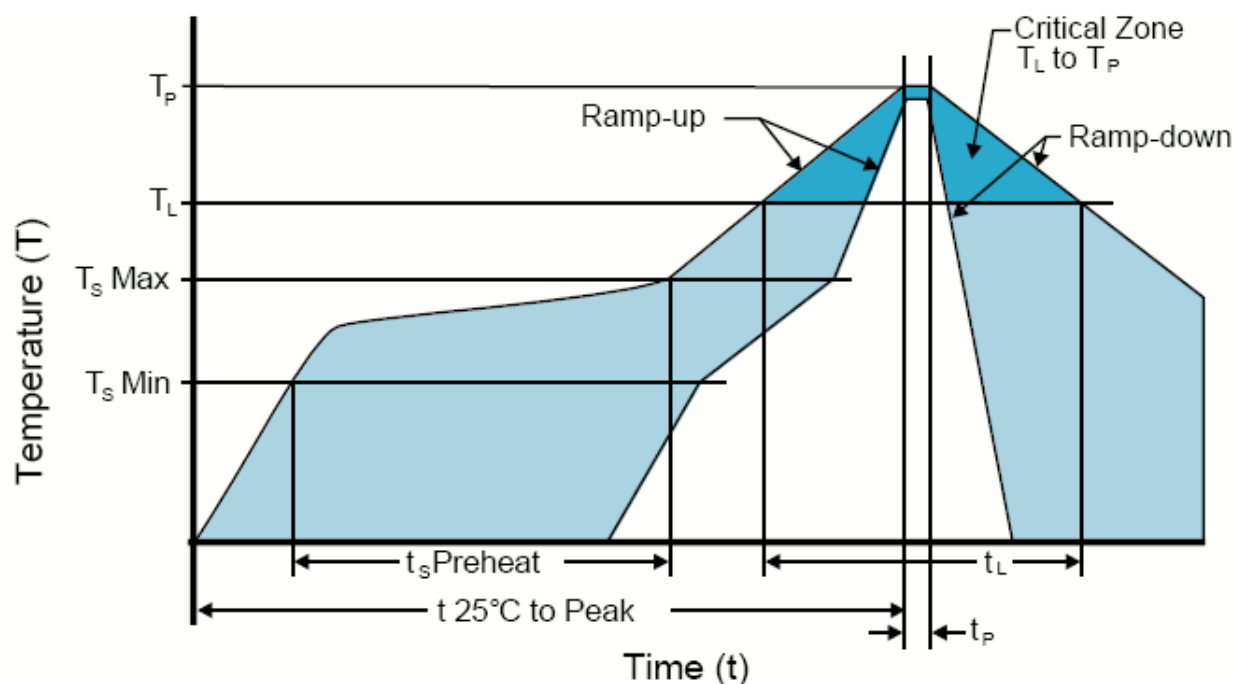
Quantity per Reel: 3,000 Units

All Dimensions in Millimeters

Compliant to EIA-481



RECOMMENDED SOLDER REFLOW METHOD



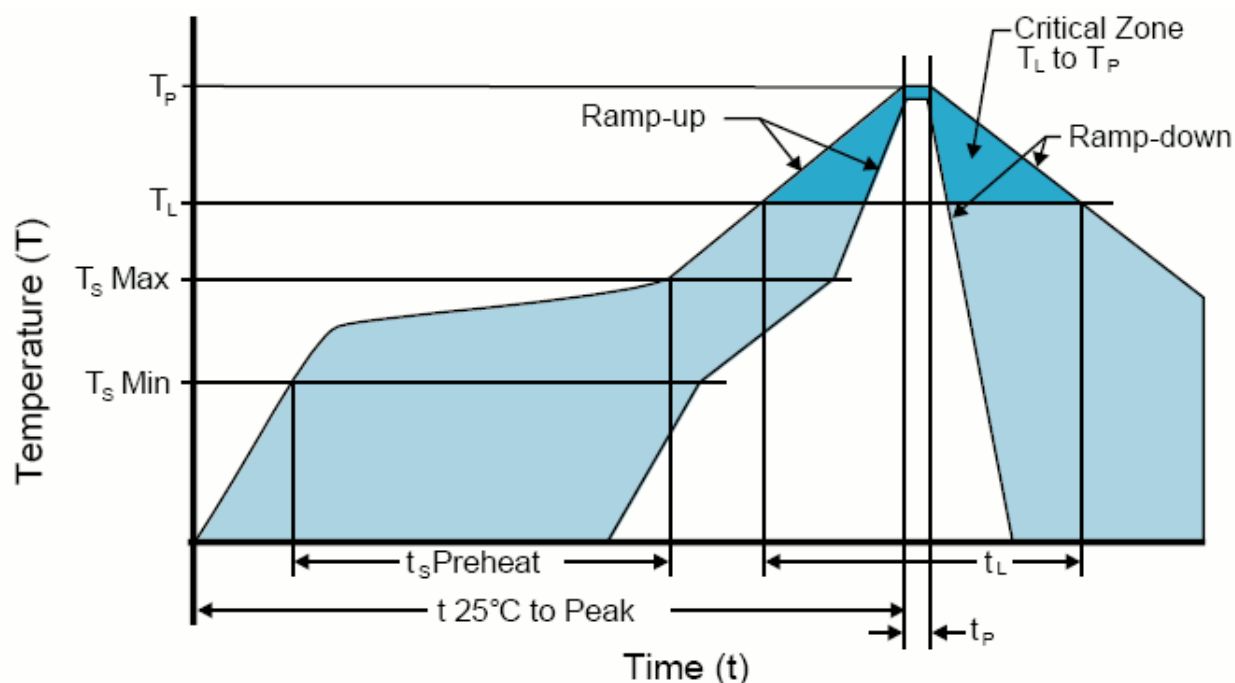
HIGH TEMPERATURE INFRARED/CONVECTION

| | |
|---|---|
| T _S MAX to T _L (Ramp-up Rate) | 3°C/Second Maximum |
| Preheat | |
| - Temperature Minimum (T _S MIN) | 150°C |
| - Temperature Typical (T _S TYP) | 175°C |
| - Temperature Maximum (T _S MAX) | 200°C |
| - Time (t _s MIN) | 60 - 180 Seconds |
| Ramp-up Rate (T _L to T _P) | 3°C/Second Maximum |
| Time Maintained Above: | |
| - Temperature (T _L) | 217°C |
| - Time (t _L) | 60 - 150 Seconds |
| Peak Temperature (T _P) | 260°C Maximum for 10 Seconds Maximum |
| Target Peak Temperature (T _P Target) | 250°C +0/-5°C |
| Time within 5°C of actual peak (t _p) | 20 - 40 Seconds |
| Ramp-down Rate | 6°C/Second Maximum |
| Time 25°C to Peak Temperature (t) | 8 Minutes Maximum |
| Moisture Sensitivity Level | Level 1 |
| Additional Notes | Temperatures shown are applied to body of device. |

High Temperature Manual Soldering

260°C Maximum for 5 Seconds Maximum, 2 times Maximum. (Temperatures shown are applied to body of device.)

RECOMMENDED SOLDER REFLOW METHOD



LOW TEMPERATURE INFRARED/CONVECTION

| | |
|--|--|
| T_S MAX to T_L (Ramp-up Rate) | 5°C/Second Maximum |
| Preheat | |
| - Temperature Minimum (T_S MIN) | N/A |
| - Temperature Typical (T_S TYP) | 150°C |
| - Temperature Maximum (T_S MAX) | N/A |
| - Time (t_s MIN) | 60 - 120 Seconds |
| Ramp-up Rate (T_L to T_P) | 5°C/Second Maximum |
| Time Maintained Above: | |
| - Temperature (T_L) | 150°C |
| - Time (t_L) | 200 Seconds Maximum |
| Peak Temperature (T_P) | 240°C Maximum |
| Target Peak Temperature (T_P Target) | 240°C Maximum 2 Times / 230°C Maximum 1 Time |
| Time within 5°C of actual peak (t_P) | 10 Seconds Maximum 2 Times / 80 Seconds Maximum 1 Time |
| Ramp-down Rate | 5°C/Second Maximum |
| Time 25°C to Peak Temperature (t) | N/A |
| Moisture Sensitivity Level | Level 1 |
| Additional Notes | Temperatures shown are applied to body of device. |

Low Temperature Manual Soldering

185°C Maximum for 10 Seconds Maximum, 2 times Maximum. (Temperatures shown are applied to body of device.)